

### **FJP9100**

### **High Voltage Power Darlington Transistor**

• Built-in Resistor at Base-Emitter :  $R_1(Typ.)$ =2000 $\Omega$ • Built-in Resistor at Base :  $R_B(Typ.)$ =700 ± 100 $\Omega$ 



Equivalent Circuit

## **NPN Silicon Darlington Transistor**

### Absolute Maximum Ratings T<sub>C</sub>=25°C unless otherwise noted

Symbol	Parameter	Value	Units	
V <sub>CBO</sub>	Collector-Base Voltage	600	V	
V <sub>CEO</sub>	Collector-Emitter Voltage	275	V	
V <sub>EBO</sub>	Emitter-Base Voltage	10	V	
I <sub>C</sub>	Collector Current (DC)	4	Α	
I <sub>CP</sub>	*Collector Current (Pulse)	6	Α	
I <sub>B</sub>	Base Current (DC)	0.5	Α	
P <sub>C</sub>	Collector Dissipation (T <sub>C</sub> =25°C)	40	W	
T <sub>J</sub>	Junction Temperature	150	°C	
T <sub>STG</sub>	Storage Temperature	- 55 ~ 150	°C	

 $R_1 \cong 2000\Omega$  $R_B \cong 700\Omega$ 

### Electrical Characteristics T<sub>C</sub>=25°C unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	$I_C = 500\mu A, I_E = 0$	600			V
BV <sub>CER</sub>	Collector-Emitter Breakdown Voltage	$I_C = 1 \text{mA}, R_{BE} = 330 \Omega$	600			V
BV <sub>CEO</sub> (sus)	Collector-Emitter Sustaining Voltage	$I_C = 1.5A$ , $I_B = 50mA$ , L=25mH	275			V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	$I_E = 500 \mu A, I_C = 0$	10			V
I <sub>CBO</sub>	Collector Cut-off Current	$V_{CB} = 600V, I_{E} = 0$			0.1	mA
I <sub>EBO</sub>	Emitter Cut-off Current	$V_{EB} = 10V, I_{C} = 0$			0.1	mA
h <sub>FE</sub>	DC Current Gain	$V_{CE} = 5V, I_{C} = 0.5A$	1000		5000	
		$V_{CE} = 5V, I_{C} = 3A$	1000			
V <sub>CE</sub> (sat)	Collector-Emitter Saturation Voltage	$I_C = 2A, I_B = 5mA$			1.5	V
V <sub>BE</sub> (sat)	Base-Emitter Saturation Voltage	$I_C = 2A, I_B = 5mA$			6.0	V
C <sub>ob</sub>	Output Capacitance	$V_{CB} = 10V, I_{E} = 0, f=1MHz$		110		pF

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<sup>\*</sup> Pulse Test: PW=300 $\mu$ s, duty Cycle=2% Pulsed

## **Typical Characteristics**

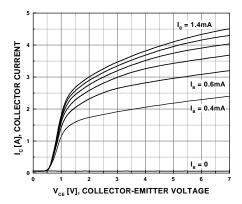


Figure 1. Static Characterstic

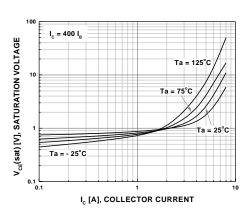


Figure 3. Collector-Emitter Saturation Voltage

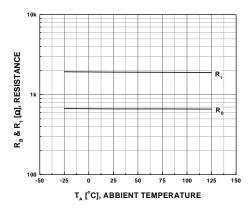


Figure 5. R<sub>B</sub> & R<sub>1</sub> vs. Ambient Temperature

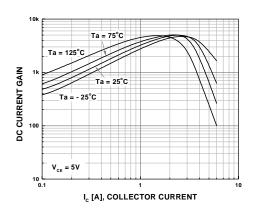


Figure 2. DC current Gain

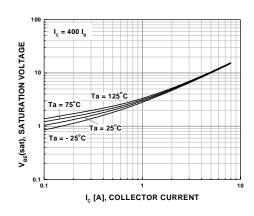


Figure 4. Base-Emitter Saturation Voltage

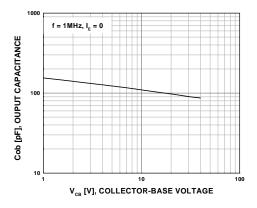


Figure 6. Output Capacitance

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# Typical Characteristics (Continued)

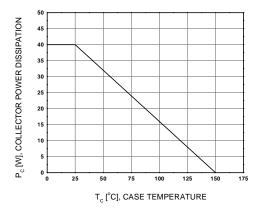


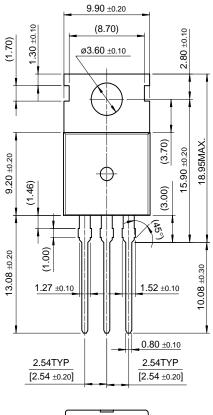
Figure 7. Power Derating

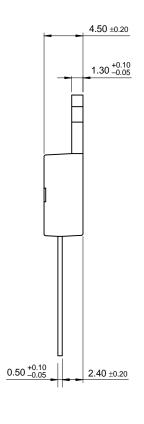
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## **Package Dimensions**

## TO-220





10.00 ±0.20

Dimensions in Millimeters

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